

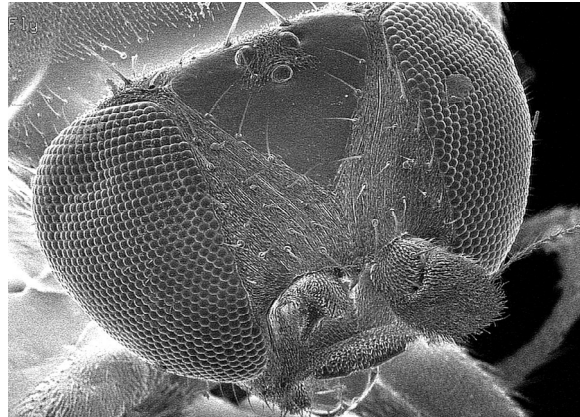
## OUR ANALYTICAL LABORATORY

With over 20 years of microscopy experience, numerous clients have benefited from our technical expertise and commitment to customer service. Our laboratory contains the following equipment:

- FE-SEM with EDX & BSE
- A unique 3D FE-SEM for quantitative surface roughness analysis down to 1 nm in vertical resolution
- Polarizing Light Microscope (PLM) and Stereo Microscopes



## Looking for SEM Services?



Call Us for an Immediate  
Appointment!



## *SEM Tech Solutions*

6 Executive Park Drive  
North Billerica, MA 01862

Phone: 978-663-9822 x232

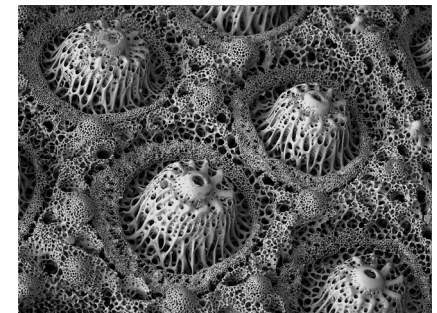
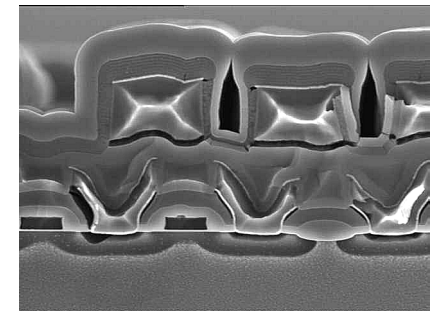
Fax: 978-663-9823

E-mail: [edobi@semtechsolutions.com](mailto:edobi@semtechsolutions.com)



FE-SEM IMAGING  
EDX ANALYSIS  
3D METROLOGY  
OPTICAL

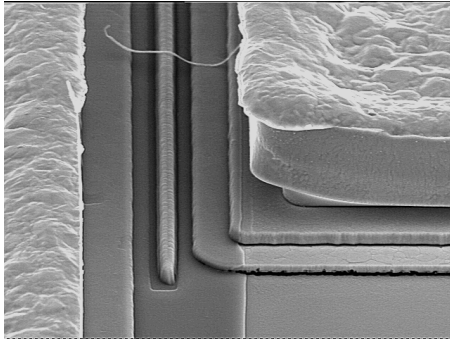
## **SEM Tech Solutions**



*“Providing microscopy services  
to a wide range of industries”*

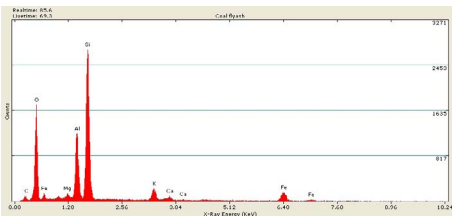
Tel: 978-663-9822  
[www.atl.semtechsolutions.com](http://www.atl.semtechsolutions.com)

## FE-SEM/EDX/BSE



Scanning Electron Microscopy (SEM), combined with Energy Dispersive X-ray Spectroscopy (EDX), is one of the most versatile and powerful analytical tools available today. SEMTech Solutions offers competitive rates and state-of-the-art equipment to satisfy your analytical services requirements. The specifications on our FE-SEM & Silicon Drift EDX are:

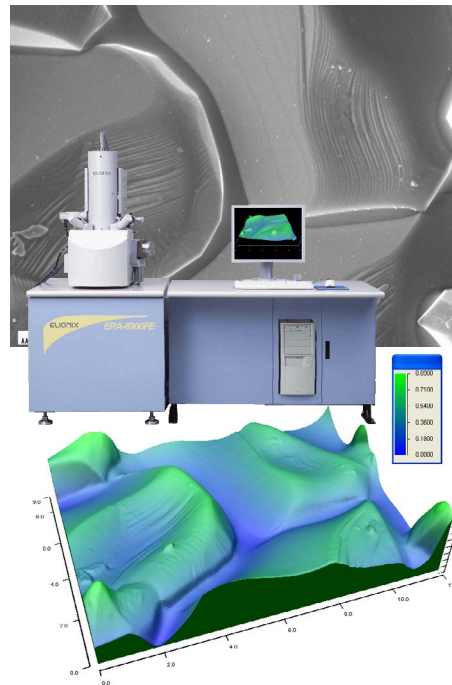
- 7nm resolution at 1kV; 1.5nm resolution at 25kV
- 8" substrate capable
- Sample tilting from -10 to 90 degrees
- < 129eV EDX resolution, with elemental detection down to Boron



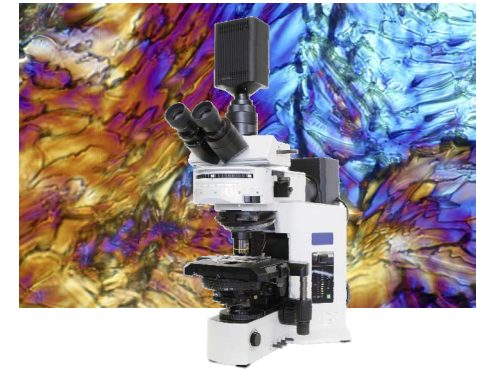
## 3D FE-SEM (e-RAM)

### “Where AFMs Can’t Go!”

Since SEMs have a depth of focus on the order of hundreds of microns and an extremely small spot (or probe) size, it is ideally suited for 3D analysis. By using 4 SE detectors, this newly unique electron-beam Roughness Analyzing Microscope (e-RAM) can measure surface roughness details down to 1nm in vertical resolution and up to several hundred microns in total depth. In addition, measurement sites are quickly visualized and measured with a wider lateral measurement range than that of an AFM.



## OPTICAL MICROSCOPY



Polarizing Light Microscopy (PLM) provides detailed information about the structure and composition of anisotropic materials. In addition, our lab has several stereo optical microscopes for sample viewing. All of our microscopes (optical & SEM) have digital imaging capabilities allowing easy report generation.

Whether your needs are for R&D or QC, we offer the expertise and fast turnaround needed to make you successful.

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